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JAP9 Rec'd PCT/PTO 07 FEB 2006

IN THE U.S. PATENT AND TRADEMARK OFFICE

February 7, 2006

Applicant : Mikio SUGIMOTO
For : MANUFACTURING METHOD OF METAL ION WATER,
WATER TREATMENT METHOD USING THE MANUFACTURING
METHOD, MANUFACTURING DEVICE OF METAL ION WATER,
AND WATER TREATMENT APPARATUS USING THE
MANUFACTURING DEVICE

PCT International Application No.: PCT/JP2004/011721

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(if known, see 37 CFR 1.5): Unknown

Atty. Docket No.: 4900.P0056US


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INFORMATION DISCLOSURE STATEMENT

Sir:

In compliance with the provisions of Rules 1.97(b)(1) and 1.98, enclosed herewith is a copy of the International Search Report, Form PTO-1449 and the references cited thereon. The relevance of these references is explained on the enclosed search report. Accordingly, further comment at this point in time should not be necessary.

Respectfully submitted,


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Encl: Copy of International Search Report
Form PTO-1449 and one copy of each reference listed
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U.S. PATENT DOCUMENTS

| Examiner Initials* | Cite No. | Document Number - Kind Code | Publication Date MM-DD-YYYY | Name of Patentee or Applicant |
|--------------------|----------|-----------------------------|-----------------------------|-------------------------------|
| | AA | | | |
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FOREIGN PATENT DOCUMENTS

| Examiner Initials* | Cite No. | Country Code - Document Number - Kind Code | Publication Date MM-DD-YYYY | Name of Patentee or Applicant | Trans. |
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| | AJ | JP 11-192492 | 07-21-1999 | SOENO | Abstract |
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NON PATENT LITERATURE DOCUMENTS

| Examiner Initials* | Cite No. | (Include Author, Title, Date, Pages, Etc.) |
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